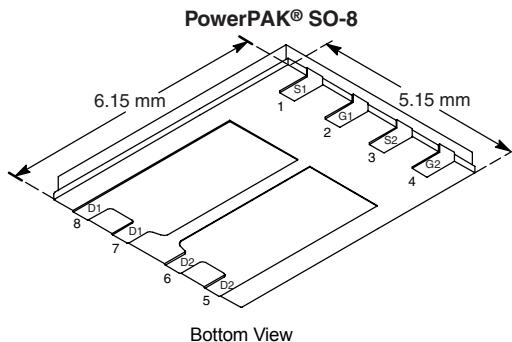


Dual N-Channel 30-V (D-S) MOSFET with Schottky Diode

PRODUCT SUMMARY			
	V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A)
Channel-1	30	0.022 at V _{GS} = 10 V	10
		0.030 at V _{GS} = 4.5 V	8
Channel-2		0.022 at V _{GS} = 10 V	10
		0.028 at V _{GS} = 4.5 V	8

SCHOTTKY PRODUCT SUMMARY		
V _{DS} (V)	V _{SD} (V) Diode Forward Voltage	I _F (A)
30	0.50 V at 1.0 A	3.0



Ordering Information: Si7872DP-T1-E3 (Lead (Pb)-free)
Si7872DP-T1-GE3 (Lead (Pb)-free and Halogen-f

FEATURES

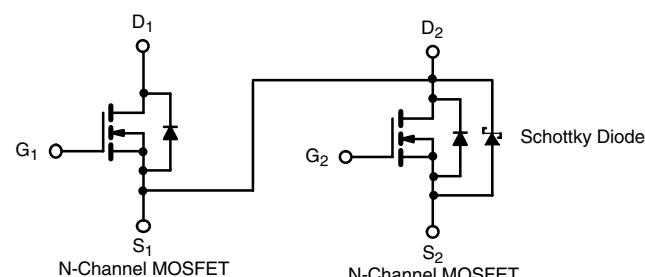
- Halogen-free Option Available
- LITTLE FOOT® Plus Schottky
- PWM Optimized
- New Low Thermal Resistance PowerPAK® Package with low 1.07 mm Profile



RoHS
COMPLIANT

APPLICATIONS

- Asymmetrical Buck-Boost DC/DC Converter



ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter	Symbol	10 s		Steady State		Unit
		Channel-1	Channel-2	Channel-1	Channel-2	
Drain-Source Voltage	V _{DS}			30		
Gate-Source Voltage	V _{GS}	± 20	± 12	± 20	± 12	V
Continuous Drain Current (T _J = 150 °C) ^a	I _D	10		6.4		A
		7		5.1		
Pulsed Drain Current	I _{DM}		30			
Continuous Source Current (Diode Conduction) ^a	I _S	2.9		1.1		
Maximum Power Dissipation ^a	P _D	3.5		1.4		W
		2.2		0.9		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150				°C
Soldering Recommendations (Peak Temperature) ^{b,c}		260				

THERMAL RESISTANCE RATINGS

Parameter	Symbol	MOSFET		Schottky		Unit
		Typical	Maximum	Typical	Maximum	
Maximum Junction-to-Ambient ^a	R _{thJA}	26	35	26	35	°C/W
		60	85	60	85	
Maximum Junction-to-Case (Drain)	R _{thJC}	4.1	6.0	4.1	6.0	

Notes:

- Surface Mounted on 1" x 1" FR4 board.
- See Solder Profile (<http://www.vishay.com/ppg?73257>). The PowerPAK SO-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

MOSFET SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min.	Typ. ^b	Max.	Unit
Static						
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	Ch-1	1.0		3.0
			Ch-2	0.8		2.0
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	Ch-1			± 100
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$	Ch-2			± 100
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-1			1
			Ch-2			100
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 85^\circ\text{C}$	Ch-1			15
			Ch-2			2000
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-1	20		
			Ch-2	20		
Drain-Source On-State Resistance ^b	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 7.5 \text{ A}$	Ch-1		0.017	0.022
			Ch-2		0.016	0.022
		$V_{GS} = 4.5 \text{ V}, I_D = 6.5 \text{ A}$	Ch-1		0.024	0.030
			Ch-2		0.020	0.028
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 7.5 \text{ A}$	Ch-1		19	
			Ch-2		21	
Diode Forward Voltage ^b	V_{SD}	$I_S = 1 \text{ A}, V_{GS} = 0 \text{ V}$	Ch-1		0.75	1.2
			Ch-2		0.47	0.5
Dynamic^a						
Total Gate Charge	Q_g	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$	Ch-1		7	11
Gate-Source Charge	Q_{gs}		Ch-2		11.5	18
Gate-Drain Charge	Q_{gd}		Ch-1		2.9	
Gate Resistance	R_G		Ch-2		3.8	
Turn-On Delay Time	$t_{d(\text{on})}$		Ch-1		2.5	
Rise Time	t_r		Ch-2		3.5	
Turn-Off Delay Time	$t_{d(\text{off})}$	$V_{DD} = 15 \text{ V}, R_L = 15 \Omega$ $I_D \geq 1 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 6 \Omega$	Ch-1		1.5	
Fall Time	t_f		Ch-2		1.8	
Source-Drain Reverse Recovery Time	t_{rr}		Ch-1		9	15
			Ch-2		10	17
			Ch-1		19	30
			Ch-2		40	66
			Ch-1		9	15
			Ch-2		9	15
			Ch-1		35	55
			Ch-2		28	45

Notes:

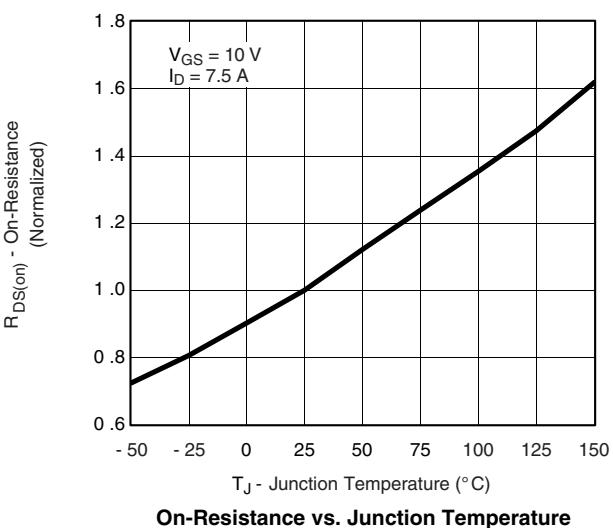
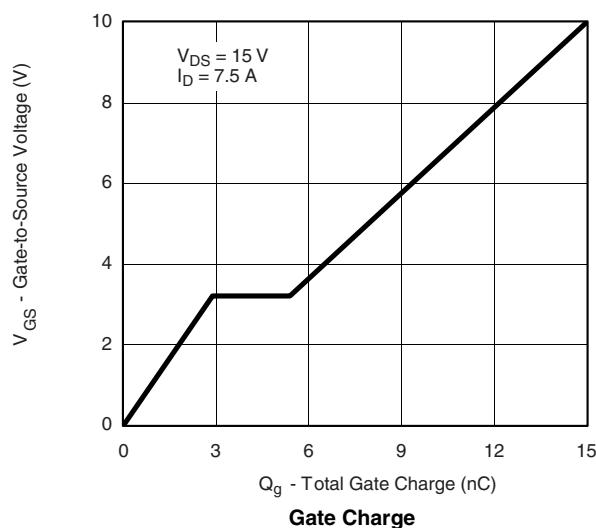
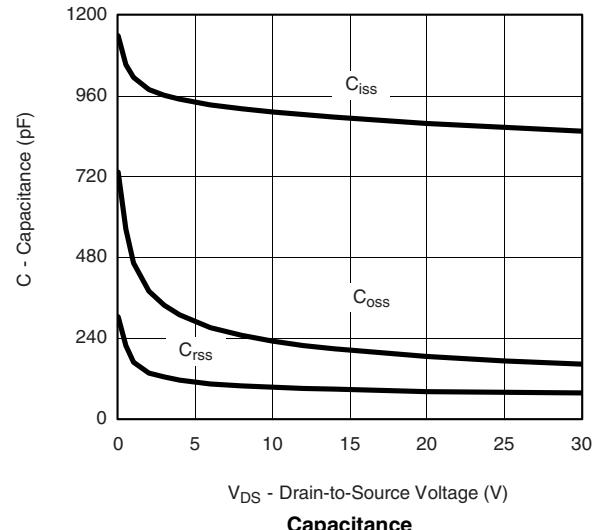
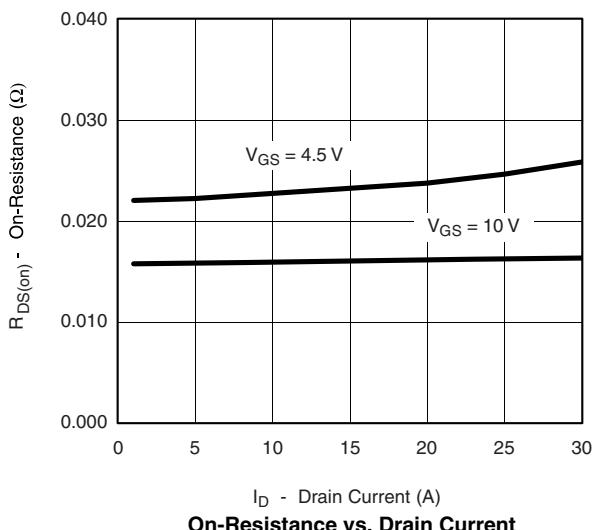
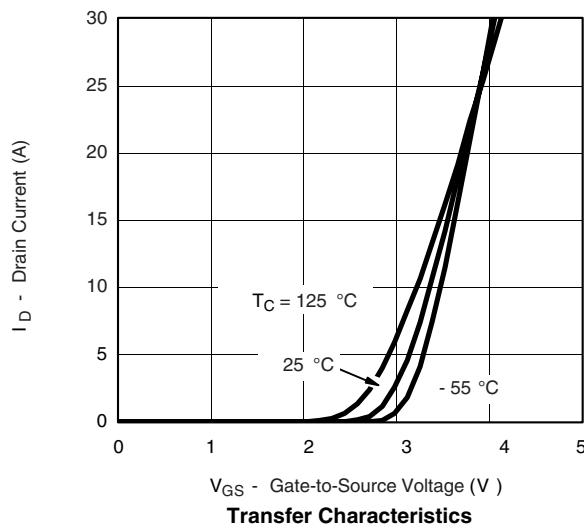
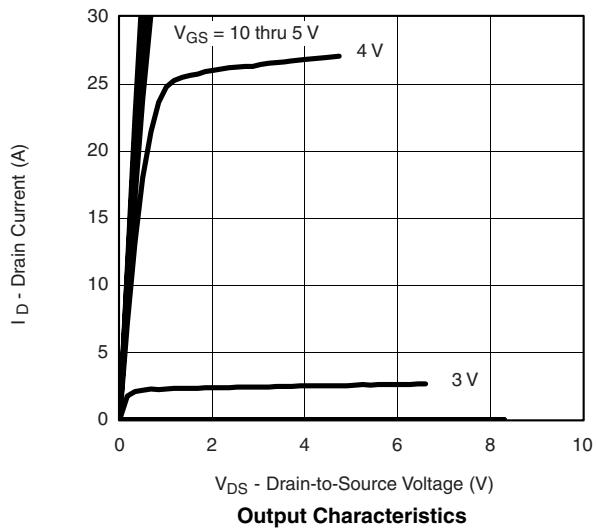
a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

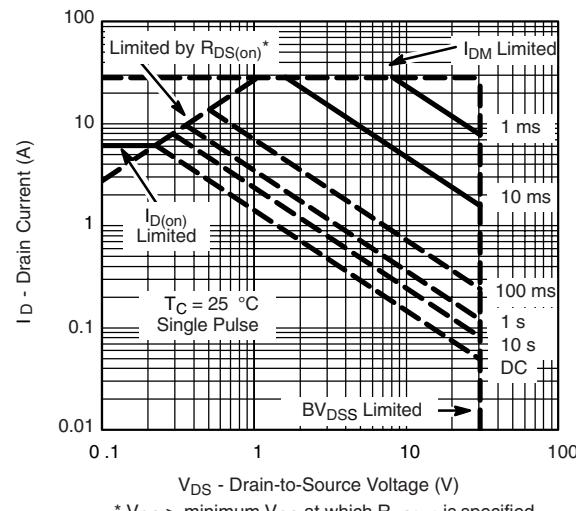
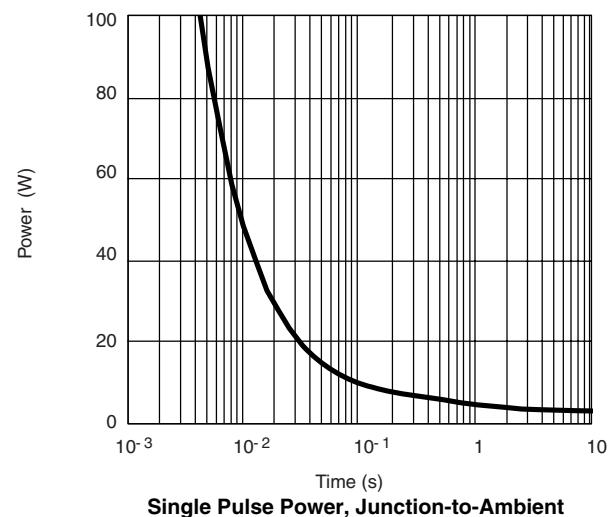
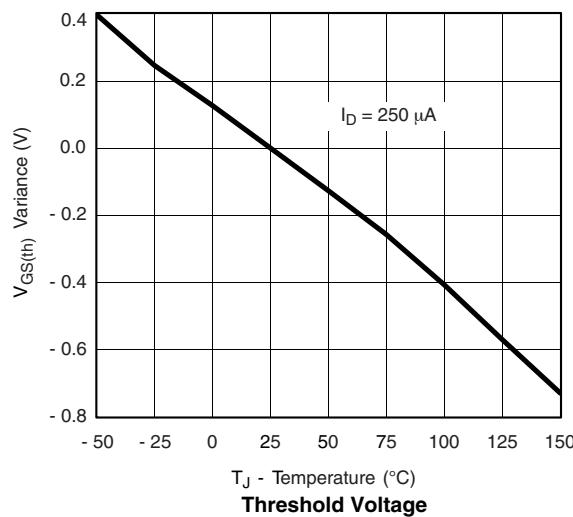
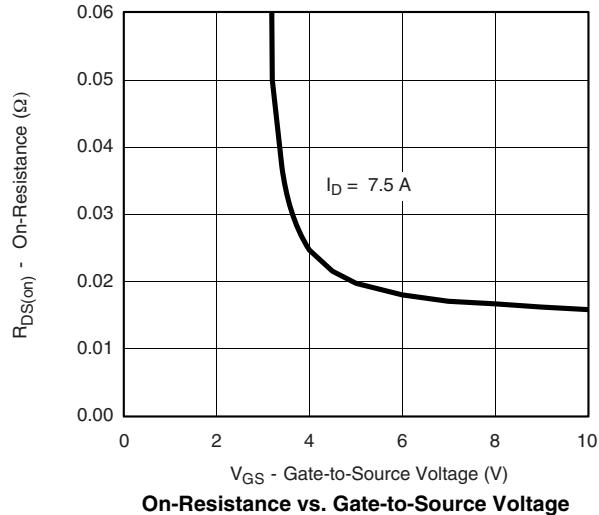
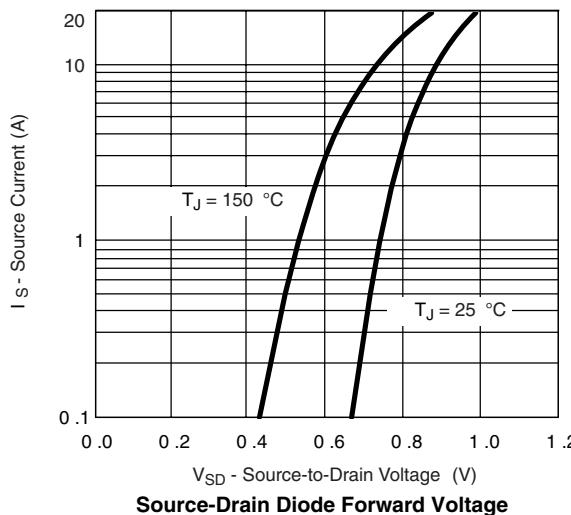
b. Guaranteed by design, not subject to production testing.

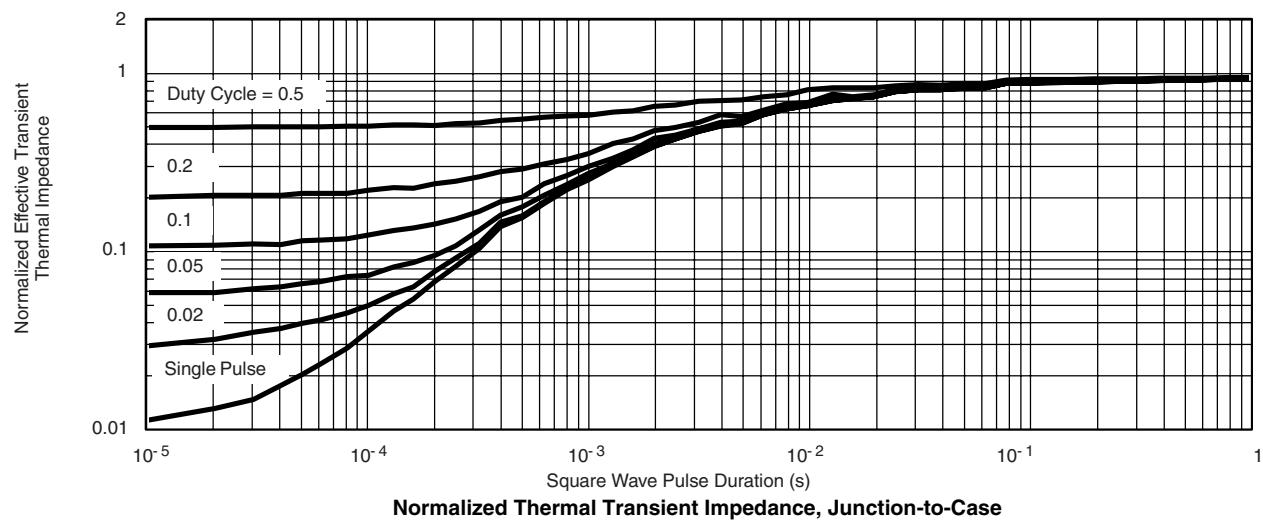
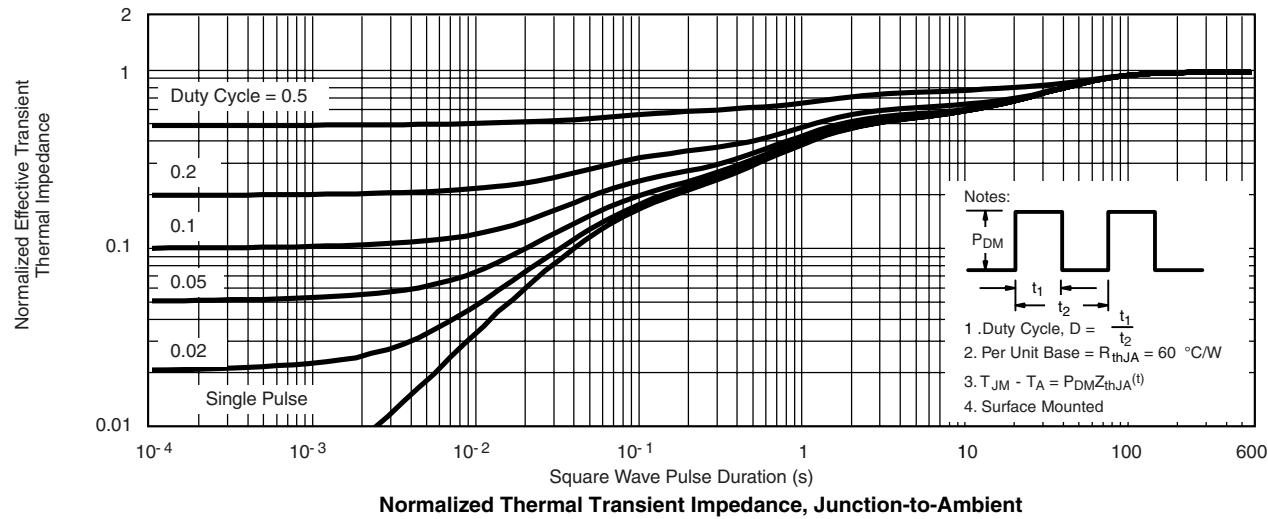
SCHOTTKY SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

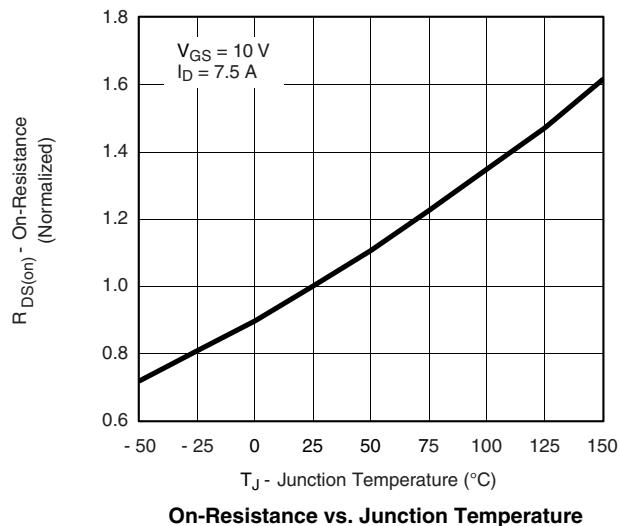
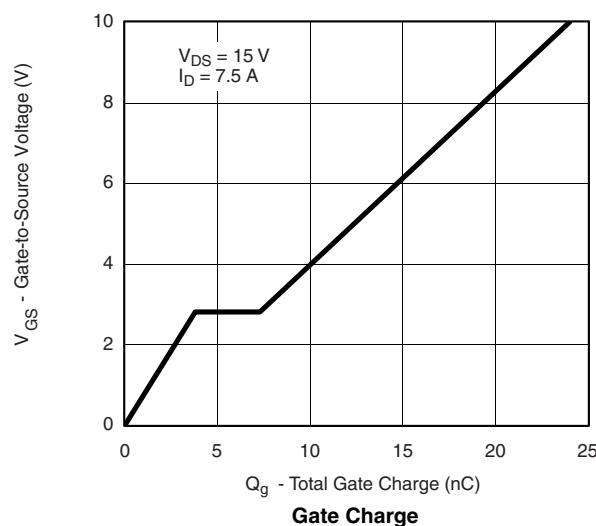
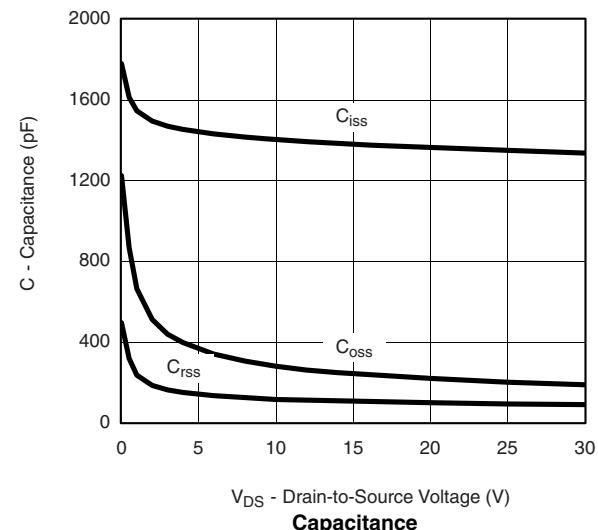
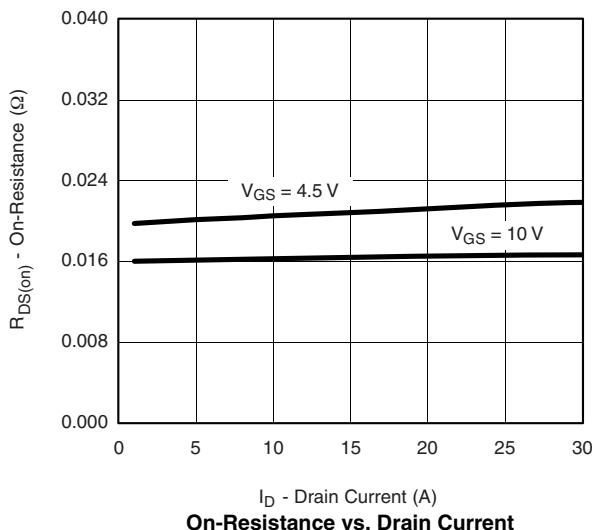
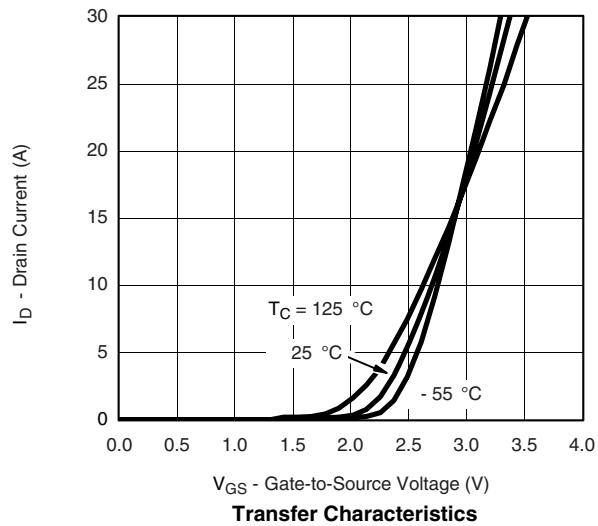
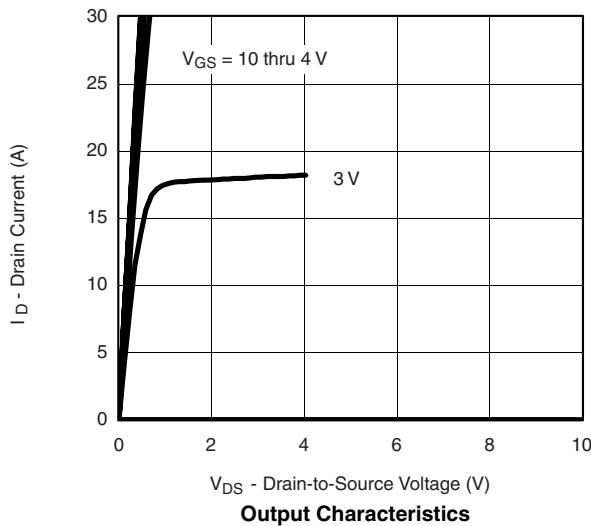
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Forward Voltage Drop	V_F	$I_F = 1.0 \text{ A}$		0.47	0.50	
		$I_F = 1.0 \text{ A}, T_J = 125^\circ\text{C}$		0.36	0.42	V
Maximum Reverse Leakage Current	I_{rm}	$V_r = 30 \text{ V}$		0.004	0.100	
		$V_r = 30 \text{ V}, T_J = 100^\circ\text{C}$		0.7	10	
		$V_r = -30 \text{ V}, T_J = 125^\circ\text{C}$		3.0	20	mA
Junction Capacitance	C_T	$V_r = 10 \text{ V}$		50		pF

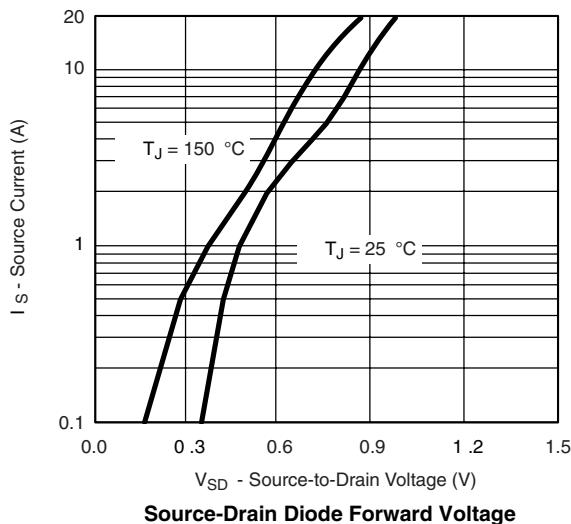
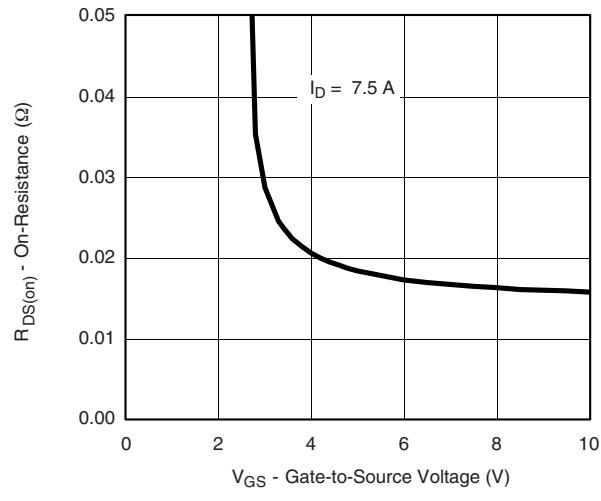
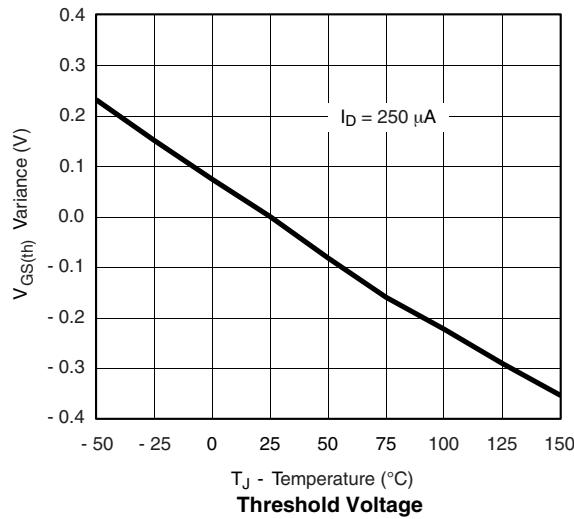
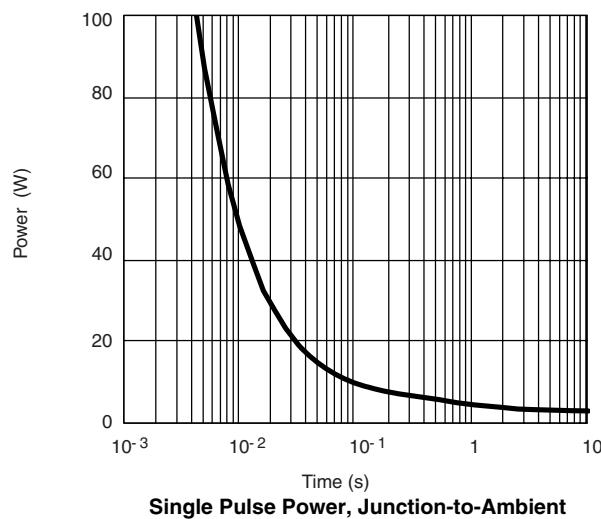
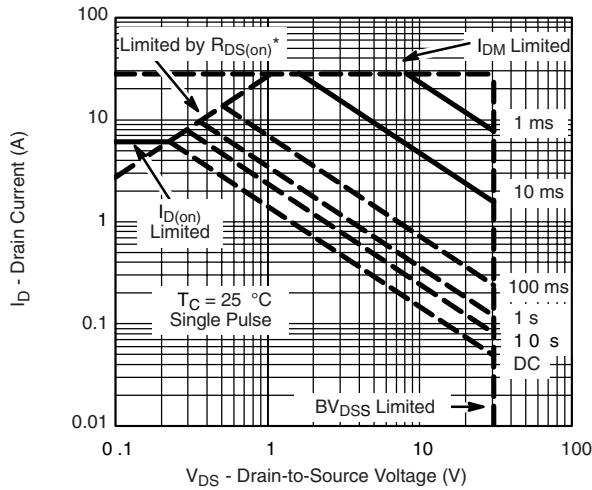
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

MOSFET CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


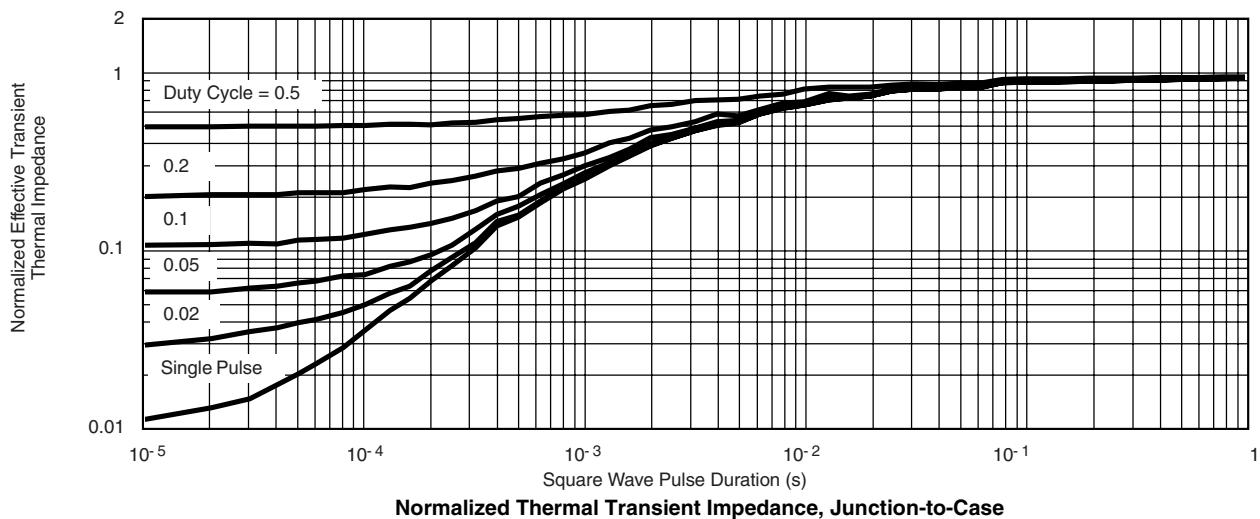
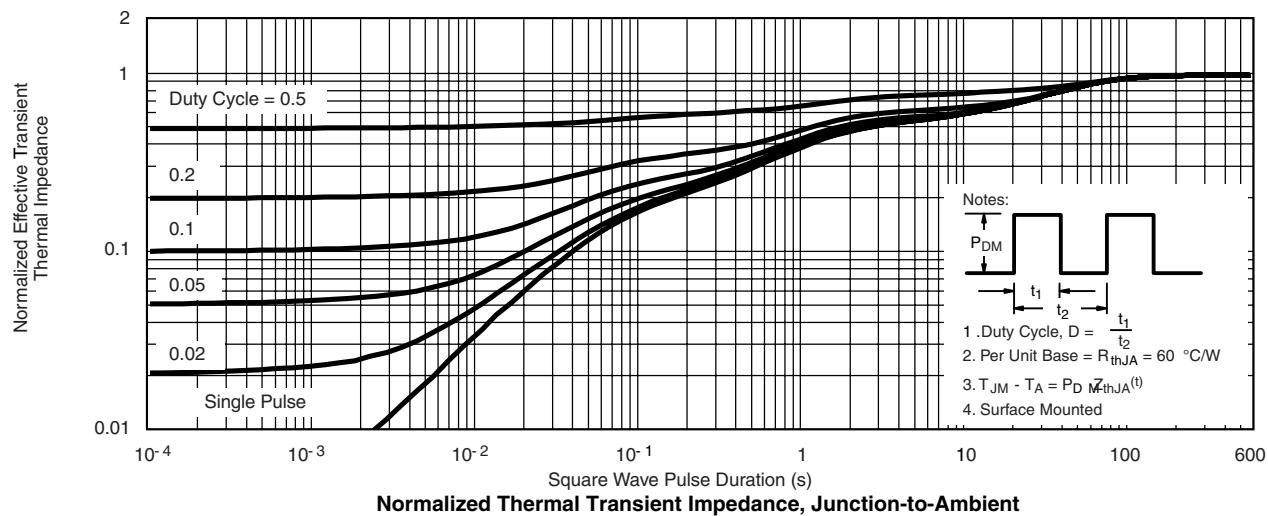
MOSFET CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

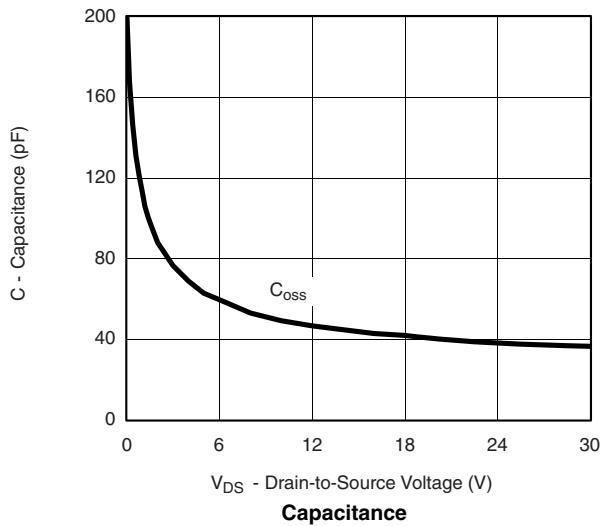
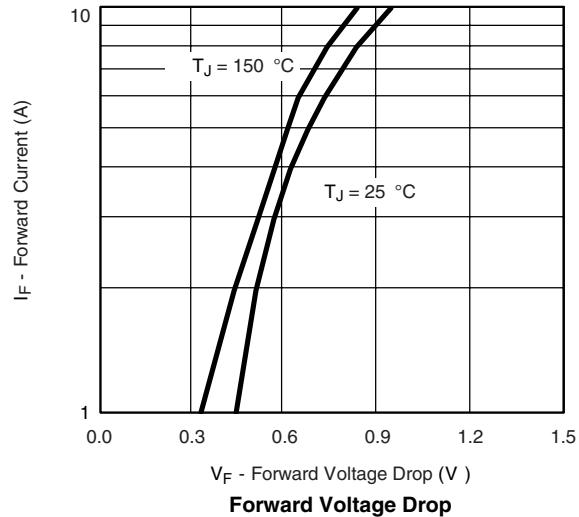
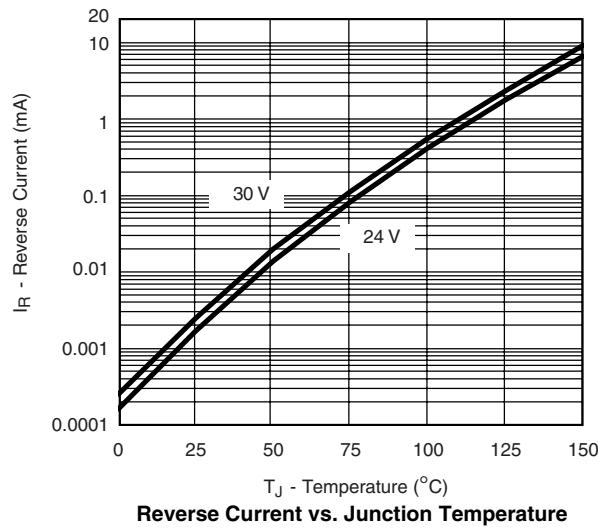
MOSFET CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


MOSFET CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

MOSFET CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Threshold Voltage

Single Pulse Power, Junction-to-Ambient

* $V_{GS} >$ minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Foot

MOSFET CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

SCHOTTKY TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


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